

<b>Notice of References Cited</b>	Application/Control No. 10/681,993		Applicant(s)/Patent Under Reexamination ISOBE, SHINOBU	
	Examiner Phallaka Kik		Art Unit 2825	Page 1 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,823,501	11-2004	Dahl, Peter	716/9
*	B	US-5,981,302	11-1999	Alswede et al.	438/15
*	C	US-5,917,197	06-1999	Alswede et al.	257/48
*	D	US-2005/0188340	08-2005	Takeoka, Sadami	716/013
*	E	US-2001/0021990	09-2001	Takeoka et al.	716/1
*	F	US-6,631,504	10-2003	Dervisoglu et al.	716/4
*	G	US-6,539,520	03-2003	Tiong et al.	716/3
*	H	US-2003/0082836	05-2003	Fetterman et al.	438/14
*	I	US-6,937,047	08-2005	Tran et al.	324/763
*	J	US-2002/0089345	07-2002	Doong et al.	324/765
*	K	US-6,680,484	01-2004	Young, Bradley Scott	257/48
*	L	US-6,577,149	06-2003	Doong et al.	324/765
*	M	US-5,640,327	06-1997	Ting, Benjamin S.	716/7

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 09178774 A	07-1997	Japan	BAYER et al.	G01R 01/073
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	NN9005325, "LSSD Boundary-Scan Design System for Reduced Pin-Count Testing", IBM Technical Disclosure Bulletin, Vol. 32, No. 12, May 1990, pp. 325-326 (4 pages).
	V	Caldwell et al., "Implications of area-array I/O for row-based placement methodology", 1998 IEEE Symposium on IC/Package Design Integration, 2 February 1998, pp. 93-98.
	W	Whetsel, "Improved Boundary Scan Design", Proceedings of International Test Conference, 21 October 1995, pp. 851-860.
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/681,993		Applicant(s)/Patent Under Reexamination ISOBE, SHINOBU	
	Examiner Phallaka Kik		Art Unit 2825	Page 2 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,155,065	10-1992	Schweiss, Helmut	438/599
*	B	US-2002/0166100	11-2002	Meding, Uwe	716/5
*	C	US-6,539,536	03-2003	Singh et al.	716/18
*	D	US-6,460,169	10-2002	Camporese et al.	716/10
*	E	US-6,348,805	02-2002	Jackson et al.	324/758
*	F	US-2002/0105049	08-2002	Barney et al.	257/511
*	G	US-6,747,445	06-2004	Fetterman et al.	324/71.1
*	H	US-2002/0004929	01-2002	Osaki et al.	716/10
*	I	US-2001/0039642	11-2001	Anzai, Takahiro	716/10
*	J	US-6,941,536	09-2005	Muranaka, Masaya	716/14
*	K	US-6,823,502	11-2004	Wingren et al.	716/9
*	L	US-6,564,362	05-2003	Osaki et al.	716/10
*	M	US-6,516,446	02-2003	Anzai, Takahiro	716/1

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/681,993		Applicant(s)/Patent Under Reexamination ISOBE, SHINOBU	
	Examiner Phallaka Kik		Art Unit 2825	Page 3 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,552,333	09-1996	Cheung et al.	438/129
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.